Change the second paragraph of 104.1.3 as shown:

A Type A or Type C PSE and Type A or Type C PD are compatible with 10BASE-T1S and 100BASE-T1 PHYs. A Type B or Type C PSE and Type B or Type C PD are compatible with 1000BASE-T1 PHYs. A Type C PSE and Type C PD are compatible with 10BASE-T1S, 100BASE-T1, and 1000BASE-T1 PHYs. Type D PSEs and Type D PDs may be incompatible with IEEE 802.3 PHYs and may lack a data entity. A Type E PSE and Type E PD are compatible with 10BASE-T1L PHYs. A Type F PSE and Type F PD are compatible with 2.5GBASE-T1, 5GBASE-T1, and 10GBASE-T1 PHYs. A Type G PSE and Type G PD are compatible with 10BASE-T1L PHYs. A Type H PSE and Type H PD are compatible with 10BASE-T1L and 100BASE-T1L PHYs.

Change 104.4.1 as shown:

For PoDL systems there are multiple types of PSEs—Type A, Type B, Type C, Type D, Type E, and Type F, Type G, and Type H consistent with 104.1.3.

Change the second paragraph of 104.4.7.3 as shown:

A digital oscilloscope or data acquisition module with a differential probe is used to observe the voltage at the MDI/PI of the PSE device under test (DUT) as shown in Figure 104–7. The input impedance, $Z_{in}(f)$, and transfer function, $H_1(f)$, of the differential probe are specified by Equation (104–1) and Equation (104–2), respectively. When measuring the ripple voltage for a Type A er, Type C, or Type G PSE as specified by Table 104–7 item (4a), f_1 = 31.8 kHz ± 1%. When measuring the ripple voltage for a Type B or Type F PSE as specified in Table 104–7 item (4a), f_1 = 318 kHz ± 1%. When measuring the ripple voltage for a Type E or Type H PSE as specified in Table 104–7 item (4a), f_1 = 3.18 kHz ± 1%.

Change the fifth paragraph in 104.4.7.3 as shown:

When measuring the ripple voltages for a Type E or Type H PSE as specified by Table 104–7 item (4b), the voltage observed at the MDI/PI with the differential probe where $f_1 = 3.18$ kHz \pm 1% is post-processed with transfer function H₂(f) specified in Equation (104–3) where $f_2 = 0.1$ MHz \pm 1%.

Change 104.5.1 as shown:

For PoDL systems there are sixeight types of PDs—Type A, Type B, Type C, Type D, Type E, and Type F, Type G, and Type H consistent with 104.1.3.

Change the second, third, and fourth paragraphs of 104.5.7.4 as shown:

The PD DUT is connected to a power supply through a dc bias coupling network as shown in Figure 104–9. The ripple and transient specifications for a Type A or Type C PD shall be met for all operating voltages in the range of V_{PD} sourced through a dc bias coupling network with MDI return loss as specified by Equation (96–12), and over the range of P_{PD}. The ripple and transient specifications for a Type B PD shall be met for all operating voltages in the range of V_{PD} sourced through a dc bias coupling network with MDI return loss as specified by Clause 97, and over the range of P_{PD}. The ripple and transient specifications for a Type E PD shall be met for all operating voltages in the range of V_{PD} sourced through a dc bias coupling network with MDI return loss as specified by Clause 146 and over the range of V_{PD} sourced through a dc bias coupling network with MDI return loss as specified by Clause 149, and over the range of P_{PD}. The ripple and transient specifications for a Type G PD shall be met for all operating voltages in the range of V_{PD} sourced through a dc bias coupling network with MDI return loss as specified by Clause 190 and over the range of V_{PD} sourced through a dc bias coupling network with MDI return loss as specified by Clause 190 and over the range of V_{PD} sourced through a dc bias coupling network with MDI return loss as specified by Clause 146 and Clause 190 and over the range of P_{PD}.

A digital oscilloscope or data acquisition module with a differential probe is used to observe the voltage at the MDI/PI. The input impedance, $Z_{in}(f)$, and transfer function, $H_1(f)$, of the differential probe are specified by Equation (104–1) and Equation (104–2), respectively. When measuring the ripple voltage for a Type A_.er Type C_. or Type G PD as specified by Table 104–11 item (3a), f_1 = 31.8 kHz ± 1%. When measuring the ripple voltage for a Type F PD as specified by Table 104–11 item (3a), f_1 = 318 kHz ± 1%. When measuring the ripple voltage for a Type E or Type H PD as specified by Table 104–11 item (3a), f_1 = 3.18 kHz ± 1%.

When measuring the ripple voltages for a Type A, er-Type C, or Type G PD as specified by Table 104–11 item (3b), the voltage observed at the MDI/PI with the differential probe where f_1 = 31.8 kHz ± 1% shall be post-processed with transfer function H₂(f) specified in Equation (104–3) where f_2 = 1 MHz ± 1%. When measuring the ripple voltages for a Type B or Type F PD as specified by Table 104–11 item (3b), the voltage observed at the MDI/PI with the differential probe where f_1 = 318 kHz ± 1% shall be post-processed with transfer function H₂(f) specified in Equation (104–3) where f_2 = 10 MHz ± 1%. When measuring the ripple voltages for a Type E or Type H PD as specified by Table 104–11 item (3b), the voltage observed at the MDI/PI with the differential probe where f_1 = 3.18 kHz ± 1% shall be post-processed with transfer function H₂(f) specified in Equation (104–3) where f_2 = 0.1 MHz ± 1%.

Change the first paragraph of 104.6.2 as shown:

The PI for Type A, Type B, Type C, and Type F PSEs and PDs shall meet the fault tolerance requirements as specified in 96.8.3. The PI for Type E, Type G, and Type H PDs shall meet the fault tolerance requirements as specified in 146.8.6.

Add Type H PD/PSE to Table 104-13:

Add "0 1 0 0 = Type H" to the bit definition of bits[15:12].

Add Type H PSE to the PICS major capabilities table in Clause 104.9.3 after line *PSETG:

*PSETH | Implements PSE Type H functionality | 104.1.3 | Provides support for requirements of Type H Power Sourcing Equipment | O | Yes [] No []

Add Type H PD to the PICS major capabilities table in Clause 104.9.3 after line *PDTG:

*PDTH | Implements PD Type H functionality | 104.1.3 Provides support for requirements of Type H Powered Device Equipment | O | Yes [] No []

Add new entry to the Powered Device (PD) table in Clause 104.9.4.3 before line PD21:

PD21 | Type H ripple and transients | 104.1.3 | In accordance with specifications shown in Table 104–11 for all operating voltages in the range of VPD sourced through a dc bias coupling network with MDI return loss as specified by Clause 146 and Clause 190, and over the range of PPD Power Sourcing Equipment | PDTH:M | Yes [] N/A []

Add new entry to the Powered Device (PD) table in Clause 104.9.4.3 before line PD23 (only, if possible, otherwise a maintenance comment would need to be filed):

PD23 | Type E ripple and transients | 104.1.3 | In accordance with specifications shown in Table 104–11 for all operating voltages in the range of VPD sourced through a dc bias coupling network with MDI return loss as specified by Clause 146, and over the range of PPD Power Sourcing Equipment | PDTE:M | Yes [] N/A []

Modify entry of the Powered Device (PD) table in Clause 104.9.4.3 in line PD24:

PD24 | Type A. <u>-er Type C.</u> or Type <u>G.</u> PD measured ripple voltage post-processing | 104.5.7.4 | With transfer function $H_2(f)$ specified in Equation (104–3) where f_2 =1 MHz ±1% | PDTA:M<u>-er</u> PDTC:M <u>PDTG:M</u> | Yes [] N/A []

Add new entry to the Powered Device (PD) table in Clause 104.9.4.3 before line PD26 (add Type E only, if possible, otherwise a maintenance comment would need to be filed):

PD26 | Type E or Type H PD measured ripple voltage post-processing | 104.5.7.4 | With transfer function H₂(f) specified in Equation (104–3) where f2=0.1 MHz ±1% | PDTE:M or PDTH:M | Yes [] N/A []

Modify entry COMEL2 in table in Clause 104.9.4.4:

COMEL2 | Type E, Type G, and Type H PSE and PD fault tolerance | 104.6.2 | The PI shall meet the fault tolerance requirements as specified in 146.8.6 | PSETE:M PSETH:M PDTE:M PDTE:M PDTE:M PDTE:M PDTH:M | Yes [] N/A []